

JLHF450B120SD3E7DN

LD3 module with NCE Gen.7 Trench/Fieldstop IGBT and Emitter Controlled diode and Pressfit/NTC

Features

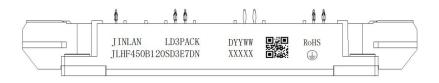
- Electrical features
 - Low V_{CEsat}
 - V_{CE(sat)} with positive temperature coefficient
 - 10µs short circuit capability
 - Maximum junction temperature 175°C
 - Low inductance case
 - Fast & soft reverse recovery anti-parallel FWD



Mechanical features

- Isolated Base Plate
- Pressfit Contact Technology

MARKING DIAGRAM



Typical Applications

- · Inverter and power supplies
- Motor Drives
- Servo Drives
- Photovoltaic/Fuel cell

JINLAN = Company Name

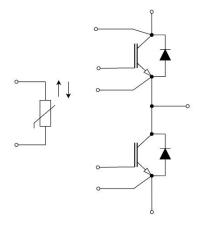
JLHF450B120SD3E7DN = Specific Device Code

YYWW = Year and Work Week Code

XXXXX = Serial Number

QR code = Custom Assembly Information

Description





Package Insulation coordination

Symbol	Description Note or test condition		Values	Unit
V _{ISOL}	Isolation test voltage	RMS,f=50Hz,t=60s	3	kV
	Material of module baseplate		Cu	
	Internal isolation	basic insulation(class 1,IEC 61140)	Al ₂ O ₃	
d _{creep}	Creepage distance	terminal to heatsink	14.5	mm
d _{creep}	Creepage distance	terminal to terminal	13.0	mm
d _{clear}	Clearance	terminal to heatsink	12.5	mm
d _{clear}	d _{clear} Clearance terminal to termi		10.0	mm
СТІ	Comparative tracking index (electrical)		>500	

Package Characteristic values

Quant at		Note or test condition			Values		
Symbol	Description	Note or test co	Min.	Тур.	Max.	Unit	
L _{sCE}	Stray inductance module				20		nH
Rcc'+EE'	Module lead resistance, terminals - chip	TC = 25 °C, per switch			1.1		mΩ
T _{STG}	Storage Temperature Range			-40		125	J
М	Mounting torque for module mounting	-Mounting according to valid application note M5, Screw		3.0		6.0	Nm
М	Terminal connection torque	-Mounting according to valid application note M6, Screw		3.0		6.0	Nm
G	Weight				345		g



IGBT

Absolute Maximum Ratings (Tc = 25°C unless otherwise noted)

Symbol	Description	Value	Unit
V _{CES}	Collector-Emitter Voltage	1200	V
V_{GES}	Gate-Emitter Voltage	±30	V
I _{CDC}	Continuous Collector Current @ Tc = 80°C (TJMAX = 175°C)	450	Α
I _{CM}	Pulsed Collector Current, t_p limited by $T_{v_j max}$	900	Α

Characteristics (Tc = 25°C unless otherwise noted)

Symbol	Parameter	Test Condition	Test Condition		Тур	Max	Unit
		I _C =300A, V _{GE} = 15 V	T _{vj} = 25 °C		1.50	2.30	
V _{CE(sat)}	Collector-Emitter Saturation Voltage		T _{vj} = 150 °C		1.70		V
		I _C =450A, V _{GE} = 15 V	T _{vj} = 25 °C		1.65	2.45	
V _{CE(sat)}	Collector-Emitter Saturation Voltage	IC -430A, VGE - 13 V	T _{vj} = 150 °C		1.85		V
$V_{GE(TH)}$	Gate-Emitter Threshold Voltage	$V_{GE} = V_{CE}$, $I_C = 5$ mA,	T _{vj} = 25°C	5.0	6.0	7.0	V
Ices	Collector-Emitter Cutoff Current	V _{GE} = 0 V, V _{CE} =1200\	/, T _{vj} = 25°C			1.0	mA
I _{GES}	Gate-Emitter Leakage Current	$V_{GE} = \pm 30 \text{ V}, V_{CE} = 0 \text{ V}$	V, T _{vj} = 25°C			±200	nA
R _{Gint}	Internal Gate Resistance	T _{vj} = 25 °	C		0.8		Ω
C _{ies}	Input Capacitance	f = 100 kHz, T _{vj} = 25 °	C, V _{CE} = 25 V,		64.2		nF
Cres	Reverse Transfer	V _{GE} = 0	V		0.32		nF
\mathbf{Q}_{G}	Gate Charge	V _{GE} = ±15 V, V _C	c = 960 V		2.2		μC
	Town On Balantina	$I_C = 450A$, $V_{CC} = 600 V$,	T _{vj} = 25 °C		260		
t _{d(on)}	Turn-On Delay Time	$V_{GE} = 15 /-5V, R_G = 5.0 \Omega$	T _{vj} = 150 °C		286		ns
	D. T.	I _C =450A, V _{CC} = 600 V,	T _{vj} = 25 °C		60		
t _r	t _r Rise Time	$V_{GE} = 15 /-5V, R_G = 5.0 \Omega$	T _{vj} = 150 °C		93		ns
		I _C = 450A, V _{CC} = 600 V,	T _{vj} = 25 °C		360		
$t_{d(off)}$	Turn-off Delay Time	$V_{GE} = 15 /-5V, R_{Goff} = 5.0 \Omega$	T _{vj} = 150 °C		440		ns
		I _C = 450A, V _{CC} = 600 V,	T _{vj} = 25 °C		53		
t _f	Fall Time	$V_{GE} = 15 /-5V, R_G = 5.0 \Omega$	T _{vj} = 150 °C		126		ns
		I _C =450A, V _{CC} = 600 V,	T _{vj} = 25 °C		26.04		
Eon	Turn-On Switching Loss per Pulse	V_{GE} = 15 /-5V, R_{G} = 5.0 Ω ($T_{Vj max}$ = 175 °C)	T _{vj} = 150 °C		52.25		mJ
		$I_C = 450A$, $V_{CC} = 600 V$,	T _v j = 25 °C		35.14		
E _{off}	Turn Off Switching Loss per Pulse	$V_{GE} = 15 /-5V, R_G = 5.0 \Omega$ $(T_{vj max} = 175 °C)$	T _{vj} = 150 °C		56.80		mJ
I _{sc}	SC Data	$V_{GE} \le 15 \text{ V}, V_{CC} = 800 \text{ V}, V_{CEmax} = V_{CES} - L_{sCE}.di/dt$	t _P ≤ 10 µs, T _{vj} =150 °C		2000		А
R _{thJC}	Thermal resistance	Junction-to-Case (per IGBT)			0.079		K/W
Тујор		Temperature under switch	ning conditions	-40		175 ¹⁾	$^{\circ}$

 $^{^{1)}}T_{vj\,op}$ > 150 $^{\circ}{\rm C}$ is only allowed for operation at overload conditions.



Diodes

Absolute Maximum Ratings (Tc = 25°C unless otherwise noted)

Symbol	Description	Value	Unit
V_{RRM}	Repetitive Peak Reverse Voltage	1200	V
I _F	Diode Continuous Forward Current @ T _C =80 ℃	450	Α
I _{FRM}	Diode Maximum Forward Current t _p =1ms	900	Α

Characteristics (Tc=25℃ unless otherwise noted)

Symbol	Parameter	Note or Test Condition		Min	Тур	Max	Unit
V _F	Diode Forward Voltage		T _v j = 25 °C		1.65	2.65	.,
		I _F = 300 A	T _{vj} = 150 °C		1.55		V
V _F	Diode Forward Voltage	1 450 A	T _v j = 25 °C		1.80	2.80	
		I _F = 450 A	T _{vj} = 150 °C		1.70		
Qr	$Q_{r} \qquad \qquad \text{Recovered Charge} \qquad \qquad \begin{aligned} I_{F} = 450 \text{ A, } V_{R} = 600 \text{ V,} \\ R_{G} = 5.0 \Omega \\ (T_{vj \text{ max}} = 175 \text{ °C}) \end{aligned}$		T _v j = 25 °C		10.66		
		T _{vj} = 150 °C		33.15		μC	
I _{RM}	Peak Reverse Recovery Current	$I_F = 450 \text{ A}, V_R = 600 \text{ V},$ $R_G = 5.0 \Omega$	T _v j = 25 °C		139		
		(T _{vj max} = 175 °C)	T _{vj} = 150 °C		199		A
E _{rec}	Reverse recovery energy	$I_F = 450 \text{ A}, V_R = 600 \text{ V},$ $R_G = 5.0 \Omega$	T _v j = 25 °C		9.85		
Liec		(T _{vj max} = 175 °C)	T _{vj} = 150 °C		24.38		mJ
R _{thJC}	Thermal resistance, junction to case	per diode			0.098		K/W
T _{vj op}		Temperature under switching conditions		-40		175 ²⁾	$^{\circ}$ C

 $^{^{2)}}T_{\nu j \, op} \! > \! 150\,^{\circ}\! \mathrm{C}$ is only allowed for operation at overload conditions.

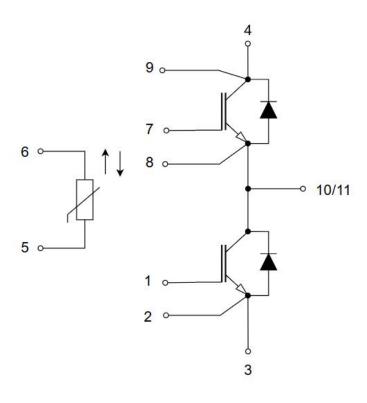
NTC Characteristics (Tc = 25°C unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
R ₂₅	Rated Resistance			5.0		kΩ
ΔR/R	R/R Deviation of R100 Tc=100 °C,R100=493.3Ω		-5		5	%
P ₂₅	Power Dissipation				20.0	mW
B _{25/50}	B-value	R ₂ =R ₂₅ exp[B _{25/50} (1/T ₂ - 1/(298.15K))]		3375		К
B _{25/80}	B-value R ₂ =R ₂ 5exp[B ₂ 5/80(1/T ₂ - 1/(298.15K))]			3411		К
B _{25/100}	B-value	R ₂ =R ₂₅ exp[B _{25/100} (1/T ₂ - 1/(298.15K))]		3433	-	К

Dec, 2024-Rev.00 4 / 8 JLHF450B120SD3E7DN

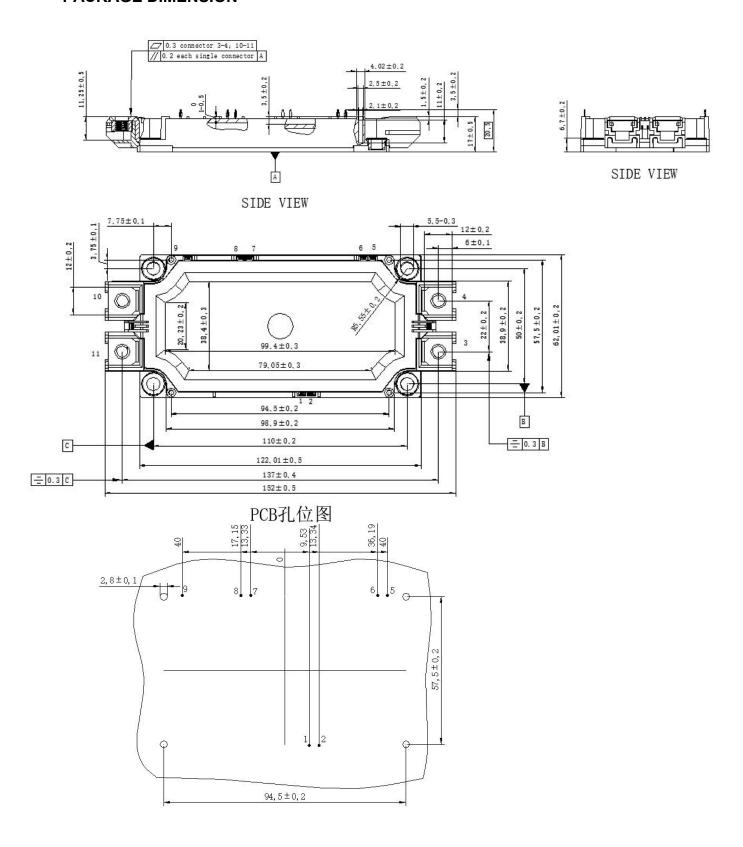


CIRCUIT DIAGRAM





PACKAGE DIMENSION





REVISION HISTORY

Document version	Date of release	Description of changes
Rev.00	2024-12-19	Preview



ATTENTION

- Any and all Jinlan power products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your Jinlan Power Semiconductor representative nearest you before using any Jinlan power products described or contained herein in such applications.
- Jinlan Power Semiconductor assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all Jinlan power modules described or contained herein.
- Specifications of any and all Jinlan power products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- Jinlan Power Semiconductor (Wuxi).co.,LTD. strives to supply high-quality high-reliability products. However,any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- In the event that any or all Jinlan power products(including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of Jinlan Power Semiconductor (Wuxi).co.,LTD.
- Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. Jinlan Power Semiconductor believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the Jinlan power product that you intend to use.
- This catalog provides information as of Dec.2024. specifications and information herein are subject to change without notice.

Dec, 2024-Rev.00 8 / 8 JLHF450B120SD3E7DN